TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TC7S08F, TC7S08FU

2-INPUT AND GATE

The TC7S08 is a high speed C²MOS 2-INPUT AND GATE fabricated with silicon gate C²MOS technology. It achieves high speed operation similar to equivalent LSTTL while maintaining the C²MOS low power dissipation.

The internal circuit is composed of 2 stages including buffer output, which enables high noise immunity and stable output.

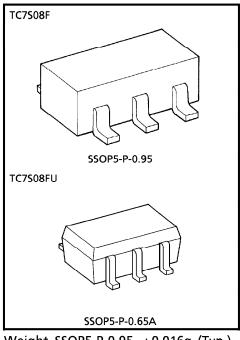
All inputs are equipped with protection circuits against static discharge or transient excess voltage.

Output currents are 1/2 compared to TC74HC series

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FEATURES

- Low Power Dissipation ICC = 1μ A (Max.) at
 - $Ta = 25^{\circ}C$
- High Noise Immunity V_{NIH} = V_{NIL} = 28% V_{CC} (Min.)
- Output Drive Capability 5 LSTTL Loads
- Symmetrical Output Impedance ... |I_{OH}| = I_{OL} = 2mA (Min.)
- Balanced Propagation Delays $t_{pLH} = t_{pHL}$
- Wide Operating Voltage Range . . . V_{CC} (opr) = 2∼6V

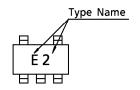


Weight SSOP5-P-0.95 : 0.016g (Typ.) SSOP5-P-0.65A : 0.006g (Typ.)

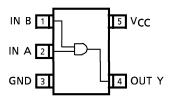
MAXIMUM RATINGS

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage Range	Vcc	-0.5~7	V
DC Input Voltage	VIN	-0.5~V _{CC} +0.5	V
DC Output Voltage	Vout	-0.5~V _{CC} + 0.5	V
Input Diode Current	Ικ	± 20	mΑ
Output Diode Current	lok	± 20	mA
DC Output Current	IOUT	± 12.5	mΑ
DC V _{CC} / Ground Current	Icc	± 25	mΑ
Power Dissipation	PD	200	mW
Storage Temperature	T _{stg}	-65∼150	°C
Lead Temperature (10s)	TL	260	°C

MARKING



PIN ASSIGNMENT (TOP VIEW)



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LOGIC DIAGRAM



RECOMMENDED OPERATING CONDITIONS

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage	Vcc	2~6	V
Input Voltage	VIN	0~V _{CC}	V
Output Voltage	Vout	0~V _{CC}	V
Operating Temperature	T _{opr}	- 40~85	°C
		$0\sim1000 \ (V_{CC}=2.0V)$	
Input Rise and Fall Time	t _r , t _f	$0 \sim 500 \ (V_{CC} = 4.5V)$	ns
		$0 \sim 400 \ (V_{CC} = 6.0V)$	

DC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC SYMB		TEST CONDITION			Ta = 25°C			Ta = -40~85°C		UNIT
CHARACTERISTIC	ARACTERISTIC STIVIBOL TEST CONDITION		Vcc	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT	
Himb Laval	inh Lovel			2.0	1.5	_	l —	1.5	_	
High-Level	V _{IH}		_	4.5	3.15	_	_	3.15	_	V
Input Voltage				6.0	4.2	_	—	4.2	—	
l avvil aval					_	_	0.5	_	0.5	
Low-Level	VIL	<u> </u>		4.5	-	_	1.35	_	1.35	V
Input Voltage				6.0	_	_	1.8	_	1.8	
	VOH	V _{IN} = V _{IH}		2.0	1.9	2.0	_	1.9	_	
restate of			$I_{OH} = -20 \mu A$	4.5	4.4	4.5	—	4.4	_	
High-Level Output Voltage				6.0	5.9	6.0	—	5.9	—	l v l
			I _{OH} = -2mA	4.5	4.18	4.31	—	4.13	_	
			$I_{OH} = -2.6 mA$	6.0	5.68	5.80	—	5.63	<u> </u>	
		V _{IN} = V _{IH} or V _{IL}		2.0	_	0.0	0.1	_	0.1	
l			$I_{OL} = 20 \mu A$	4.5	l —	0.0	0.1	_	0.1	
Low-Level Output Voltage	VOL			6.0	 	0.0	0.1	<u> </u>	0.1	v I
			I _{OL} = 2mA	4.5	_	0.17	0.26	_	0.33	
			$I_{OL} = 2.6 mA$	6.0	—	0.18	0.26	_	0.33	
Input Leakage	1	V _{IN} = V _{CC} or GND		6.0			± 0.1		+10	
Current	IN			0.0	_	_	- 0.1	_	± 1.0	
Quiescent	laa	Var. Var. or CND		6.0			1.0		10.0	μ A
Supply Current	lcc	NM = _ CC _ 0	$V_{IN} = V_{CC}$ or GND		_	_	1.0		10.0	

Output currents are 1/2 compared to TC74HC series models.

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AC ELECTRICAL CHARACTERISTICS ($C_L = 15p$	oF, Input $t_r = t_f = 6$ ns, $V_{CC} = 5V$)
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CHARACTERISTIC	SYMBOL	TEST CONDITION	Т	UNIT		
CHARACTERISTIC	STIVIBUL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Output Transition	tTLH			E	10	nc
Time	tTHL	_		3	10	ns
Propagation Delay	t _{pLH}			7	15	200
Time	t _{pHL}	_	_	'	13	ns

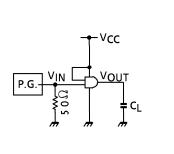
AC ELECTRICAL CHARACTERISTICS ($C_L = 50pF$, Input $t_r = t_f = 6ns$)

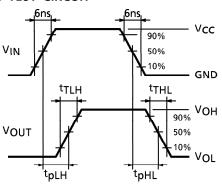
	I			_	. 250		т	0.000	
CHARACTERISTIC SYMBOL	SYMBOL	TEST CONDITION		Ta = 25°C			Ta = -4	UNIT	
	TEST CONDITION		MIN.	TYP.	MAX.	MIN.	MAX.	Oivii	
Output Transition 4		2.0	_	50	125	_	155		
Output Transition Time	t _{TLH}	_	4.5	 —	14	25	_	31	ns
Time	[†] THL		6.0	—	12	21	—	26	
Dramagation Dalou		2.0	_	48	100	_	125		
Propagation Delay Time	t _{pLH}	_	4.5	l —	12	20	<u> </u>	25	ns
Time t _{pHL}		6.0	—	9	17	—	21		
Input Capacitance	CIN	_		_	5	10	_	10	
Power Dissipation Capacitance	C _{PD}	(Note 1)			10	_	_	_	pF

Note 1: CpD defined as the value of internal equivalent capacitance of IC which is calculated from the operating current consumption without load (refer to Test Circuit).

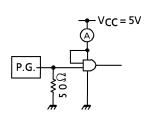
Average operating current can be obtained by the equation hereunder.

SWITCHING CHARACTERISTICS TEST CIRCUIT





ICC (opr) TEST CIRCUIT



Input waveform is the same as that in case of switching characteristics test.